



中国认可
国际互认
检测
TESTING
CNAS L6478



TEST REPORT

Reference No...... : WTF23F09203360E
Applicant..... : Mid Ocean Brands B.V.
Address..... : 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon,
Hong Kong
Manufacturer : 114628
Address..... : ---
Product Name..... : 20W EU plug with Type-C
Model No...... : MO2155
Test specification..... : EN 55032:2015+A11:2020+A1:2020
EN 55035:2017+A11:2020
EN IEC 61000-3-2:2019+A1:2021
EN 61000-3-3:2013+A1:2019+A2:2021
Date of Receipt sample : 2023-09-20
Date of Test : 2023-09-21 to 2023-09-25
Date of Issue..... : 2023-09-28
Test Report Form No...... : WEI-55032A-04A
Test Result..... : Pass

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of approver.

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1 Test Summary

EMISSION				
Test Item	Test Standard		Class / Severity	Result
Mains Terminal Disturbance Voltage, 150kHz to 30MHz	EN 55032:2015+A11:2020+A1:2020		Table A.10	Pass
Radiated Emission, 30MHz to 1000MHz	EN 55032:2015+A11:2020+A1:2020		Table A.4	Pass
Harmonic Current Emission	EN IEC 61000-3-2:2019+A1:2021		Class A	Pass**
Voltage Fluctuation and Flicker	EN 61000-3-3:2013+A1:2019+A2:2021		Clause 5	Pass
IMMUNITY (EN 55035:2017+A11:2020)				
Test Item	Test Method	Class / Severity	Performance Criteria	Result
Electrostatic Discharge(ESD)	IEC 61000-4-2:2008	±4 Kv Contact ±8 Kv Air	B	Pass
Continuous RF Electromagnetic Field Disturbances	IEC 61000-4-3: 2006+A1+A2	3V/m, 80%, 1kHz, Amp. Mod.	A	Pass
Electrical Fast Transients (EFT)	IEC 61000-4-4:2012	AC ±1.0Kv DC ±0.5Kv	B	Pass
Surge	IEC 61000-4-5:2005	±1Kv D.M.† ±2Kv C.M.‡	B	Pass
Continuous Induced RF Disturbances, 0.15MHz to 10MHz	IEC 61000-4-6:2008	3Vr.m.s.(emf), 80%, 1kHz Amp. Mod.	A	Pass
Continuous Induced RF Disturbances, 10MHz to 30MHz		3 to 1Vr.m.s.(emf), 80%, 1kHz Amp. Mod	A	Pass
Continuous Induced RF Disturbances, 30MHz to 80MHz		1Vr.m.s.(emf), 80%, 1kHz Amp. Mod	A	Pass
Power-Frequency Magnetic Field	IEC 61000-4-8:2009	1A/m	A	N/A
Voltage Dips	IEC 61000-4-11:2004	< 5 % U _T * for 0.5per	B	Pass
		70 % U _T * for 25/30per	C	Pass
Voltage Interruptions	IEC 61000-4-11:2004	< 5 % U _T * for 250/300per	C	Pass

Remark:

- Pass Test item meets the requirement
 Fail Test item does not meet the requirement
 N/A Test case does not apply to the test object
 A.M Amplitude Modulation
 † Differential Mode
 ‡ Common Mode
 * U_T is the nominal supply voltage
 ** According to EN IEC 61000-3-2 which states: "For the following categories of equipment limits are not specified in this edition of the standard. Equipment with a rated power of 75W or less, other than lighting equipment" Therefore there is no need for harmonics test to be performed on this product and deemed to fulfil emission requirements without testing.



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3 General Information

3.1 General Description of E.U.T.

Product Name : 20W EU plug with Type-C

Model No. : MO2155

Remark : ---

3.2 Details of E.U.T.

Technical Data : Input: 100-240V~, 50/60Hz, 0.5A;
Output: DC 5V, 3.0A, 15W; DC 9V, 2.22A, 20W; DC 12V, 1.67A, 20W

3.3 Description of Support Units

The EUT has been tested as an independent unit. MO2155 is the test sample. The DV&RE tests were performed in the condition of AC 240V/50Hz input. The other tests were performed in the condition of AC 230V/50Hz input. All tests were performed with a mobile phone specified by laboratory.

3.4 Standards Applicable for Testing

The tests were performed according to following standards:

EN 55032:2015+A11:2020+A1:2020

Electromagnetic compatibility of multimedia equipment —
Emission Requirements

EN 55035:2017+A11:2020

Electromagnetic compatibility of multimedia equipment -
Immunity requirements

EN IEC 61000-3-2:2019+A1:2021

Electromagnetic compatibility (EMC) -- Part 3-2: Limits - Limits
for harmonic current emissions (equipment input current up to
and including 16 A per phase).

EN 61000-3-3:2013+A1:2019+A2:2021

Electromagnetic compatibility (EMC) -- Part 3-3: Limits -
Limitation of voltage changes, voltage fluctuations and flicker
in public low-voltage supply systems, for equipment with rated
current ≤ 16 A per phase and not subject to conditional
connection.



3.5 Test Facility

The test facility has a test site registered with the following organizations:

- **ISED – Registration No.: 21895**

Waltek Testing Group (Foshan) Co., Ltd. has been registered and fully described in a report filed with the Innovation, Science and Economic Development Canada (ISED). The acceptance letter from the ISED is maintained in our files. Registration ISED number: 21895, March 12, 2019

- **FCC – Registration No.: 820106**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 820106, August 16, 2018

- **NVLAP – Lab Code: 600191-0**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP/NIST). NVLAP Code: 600191-0.

This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

3.6 Subcontracted

Whether parts of tests for the product have been subcontracted to other labs:

☐ Yes ☒ No

If Yes, list the related test items and lab information:

Test items: ---

Lab information: ---

3.7 Abnormalities from Standard Conditions

None.



4 Equipment Used during Test

☐ Mains Terminal Disturbance Voltage (Conducted Emission) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESR3	102423	Valid
2.	LISN	R&S	ENV216	101343	Valid
3.	Cable	HUBER+SUHNER	CBL2-NN-6M	223NN624	Valid
4.	Switch	CD	RSU-A4 18G	RSUA4008	Valid
☒ Mains Terminal Disturbance Voltage (Conducted Emission) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESCI	101178	Valid
2.	LISN	R&S	ENV216	101215	Valid
3.	Cable	HUBER+SUHNER	CBL2-NN-6M	6102701	Valid
4.	Switch	ESE	RSU/M2	---	Valid
☐ Mains Terminal Disturbance Voltage (Conducted Emission) 3#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESR3	102842	Valid
2.	LISN	R&S	ENV216	101542	Valid
3.	Cable	YIHENG	LMR195UF-NMNM-2.5	---	Valid
4.	Manual RF Switch	YIHENG	SW-2	RSU0402	Valid
☒ Radiated Emission (30MHz to 1GHz) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	-	Valid
2.	EMI Test Receiver	R&S	ESR7	101566	Valid
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9162	9162-117	Valid
4.	Coaxial Cable (below 1GHz)	H+S	CBL3-NN-12+3 m	214NN320	Valid
☐ Radiated Emission (30MHz to 1GHz) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	YIHENG	10m×5.3m×3.5m	YH2021071804	Valid
2.	EMI Test Receiver	R&S	ESR7	102454	Valid
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9163	01418	Valid
4.	Coaxial Cable (below 1GHz)	Times-Microwave Systems	LMR240UF-NMSM-7.5	-	Valid
☐ Radiated Emission (1GHz to 6GHz) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	-	Valid
2.	EMI Test Receiver	R&S	ESR7	101566	Valid



3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA 9120 D	01561	Valid
4.	Coaxial Cable (above 1GHz)	Times-Microwave	CBL5-NN	-	Valid
5.	Preamplifier	Lunar E M	LNA1G18-40	20160501002	Valid
☐ Radiated Emission (1GHz to 6GHz) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	YIHENG	10m×5.3m×3.5m	YH2021071804	Valid
2.	EMI Test Receiver	R&S	ESR7	102454	Valid
3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA9120D	02465	Valid
4.	Coaxial Cable (above 1GHz)	Times-Microwave Systems	SFT205-NMSM-7	-	Valid
5.	Preamplifier	Tonscend	TAP0118045	AP21J806168	Valid
☒ Harmonics and Flicker Measuring System					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	Harmonics and Flicker Measuring System	YUANFANG	HFM-3000	V200	Valid
☒ ESD					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	ESD Simulator	TESEQ	NSG437	521	Valid
☒ EFT & Voltage Dips and Interruptions					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMS test system	TESEQ	NSG3040	1858	Valid
☒ Surge					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	Surge Simulator	TESEQ	NSG3060	1395	Valid
☒ Injected Currents					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	Conducted Immunity test system	TESEQ	NSG4070	31469	Valid
2.	CDN	TESEQ	CDN M016	31586	Valid
3.	6dB Attenuator	TESEQ	ATN6075	32122	Valid
☒ Radio-frequency Electromagnetic Fields					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	RF Power Amplifier	OPHIR	5225R	1051/1712	Valid
2.	RF Power Amplifier	OPHIR	5293RE	1051/171	Valid
3.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP9128E-SPECIAL	142	Valid
4.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP 9149	476	Valid



5.	RF signal generator	Agilent	N5181A	MY48180720	Valid
6.	Power meter	RS	NRP6A	101133	Valid
7.	Power meter	RS	NRP6A	101134	Valid

☐: Not Used

☒: Used

4.1 Software List

Description	Manufacturer	Model	Version
EMI Test Software (Conducted Emission 1#)	FARATRONIC	EZ-EMC	EMEC-3A1
EMI Test Software (Conducted Emission 2#)	FARATRONIC	EZ-EMC	CON-03A1
EMI Test Software (Conducted Emission 3#)	FARATRONIC	EZ-EMC	COM 3A1.1
EMI Test Software (Radiated Emission 1#)	FARATRONIC	EZ-EMC	RA-03A1-1
EMI Test Software (Radiated Emission 2#)	FARATRONIC	EZ-EMC	RA-03A1-1
Harmonics and Flicker Test Software	YUANFANG	HFM-3000	V2.00.120
Radiated Immunity Test Software	TONSCEND	JS35-RS	V2.0.1.7

4.2 Measurement Uncertainty

Test Item	Frequency Range	Uncertainty	Note
Conducted Emission	150kHz~30MHz	±2.6dB	(1)
Radiated Emission	30MHz~1GHz	±4.5dB	(1)
Radiated Emission	1GHz~6GHz	±4.5dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.



4.3 Special Accessories and Auxiliary Equipment

Item	Equipment	Technical Data	Manufacturer	Model No.	Serial No.
1.	Mobile Phone	---	iPhone	12	DNPDM0RU0DYQ

4.4 Decision Rule

Compliance or non-compliance with a disturbance limit shall be determined in the following manner.

If U_{LAB} is less than or equal to U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.

If U_{LAB} is greater than U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit.

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5 Emission Test Results

5.1 Mains Terminals Disturbance Voltage, 150 kHz to 30MHz

Test Requirement.....	: EN 55032 Annex A.3
Test Method.....	: EN 55032 Annex A.3
Test Result.....	: Pass
Frequency Range.....	: 150kHz to 30MHz
Class/Severity.....	: Table A.10 of EN 55032
Classification.....	: ClassB

5.1.1 E.U.T. Operation

Operating Environment:

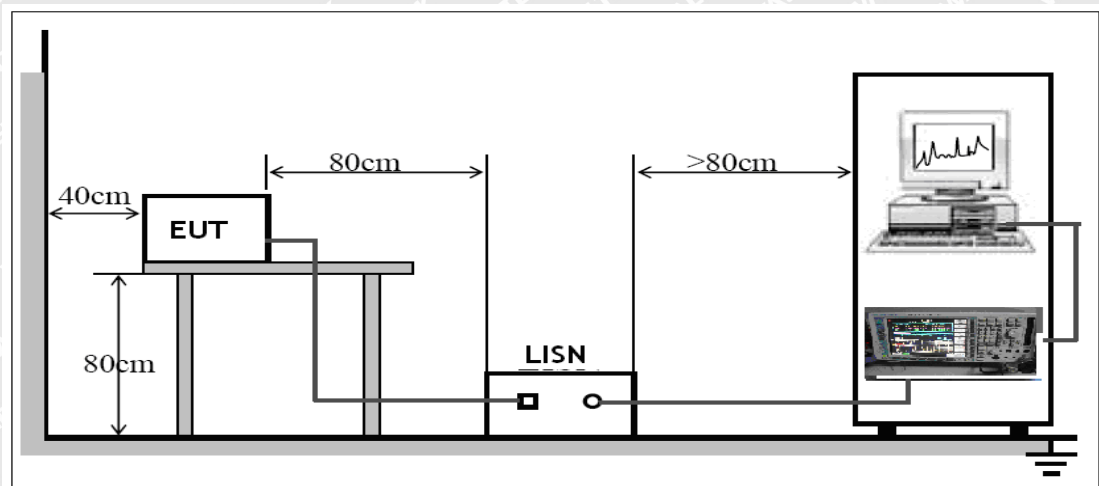
Temperature	: 24.8°C
Humidity.....	: 49.3%RH
Atmospheric Pressure.....	: 101.2kPa

EUT Operation:

Input Voltage	: AC 240V/50Hz
Operating Mode.....	: Working mode

5.1.2 Block Diagram of Test Setup

The Mains Terminals Disturbance Voltage tests were performed in accordance with the CISPR 16-1-2.



5.1.3 Measurement Data

The maximised peak emissions from the EUT was scanned and measured for both the Live and Neutral Lines. Quasi-peak & average measurements were performed if peak emissions were within 6dB of the average limit line.



5.1.4 Corrected Amplitude & Margin Calculation

The Corrected factor is calculated by adding LISN VDF(Voltage Division Factor), Cable Loss and Transient Limiter Attenuation. The basic equation is as follows:

$$\text{Measurement} = \text{Reading Level} + \text{Correct Factor}$$

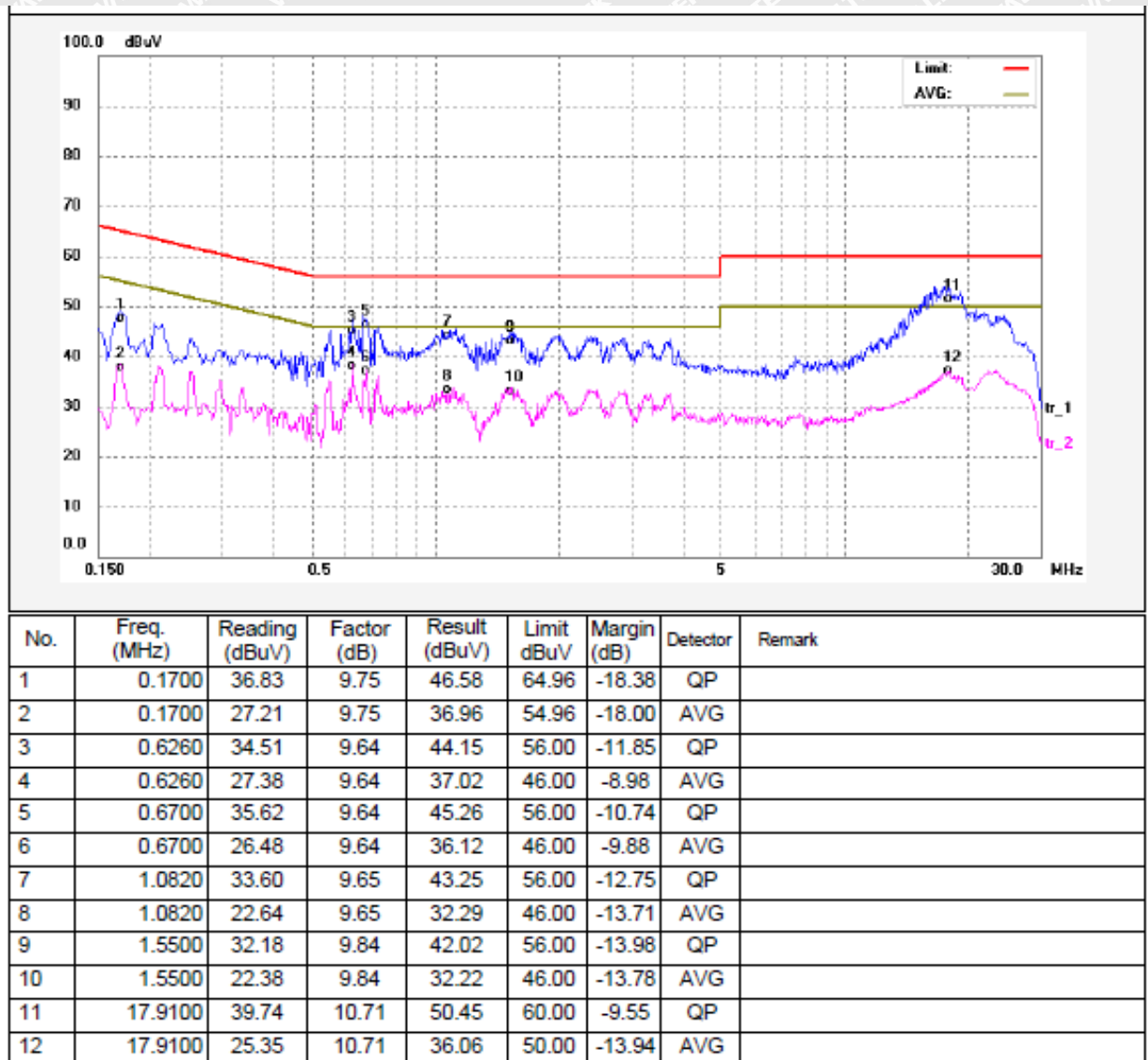
$$\text{Correct Factor} = \text{LISN VDF} + \text{Cable Loss}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the limit. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Measurement} - \text{Limit}$$

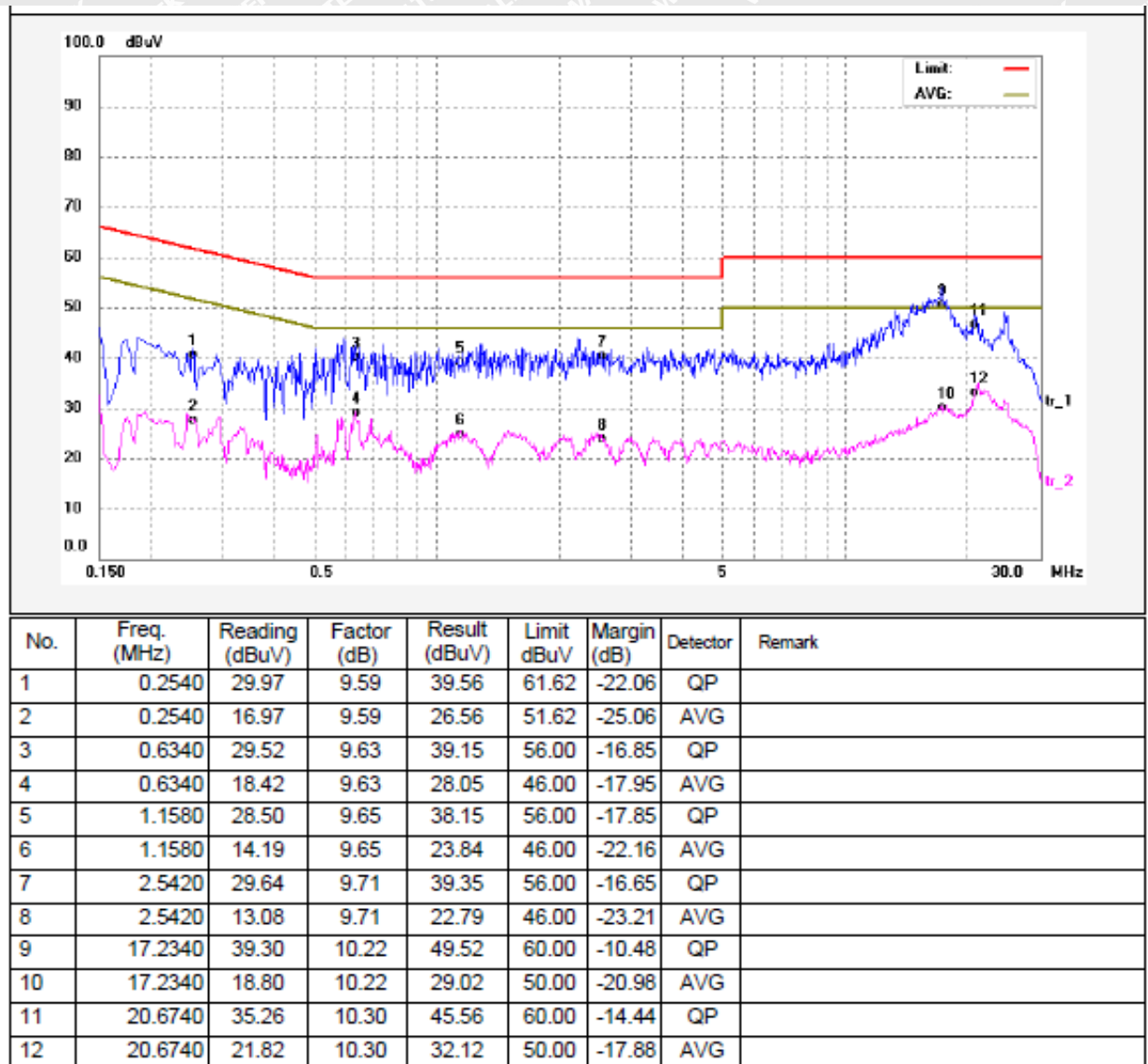
5.1.5 Mains Terminals Disturbance Voltage Test Data

Live Line





Neutral Line





5.2 Radiated Emission, 30MHz to 1GHz

Test Requirement	: EN 55032 Annex A.2
Test Method	: EN 55032 Annex A.2
Test Limit	: Table A.4 of EN 55032
Test Result	: Pass
Frequency Range	: 30MHz to 1000MHz
Class	: Class B

5.2.1 E.U.T. Operation

Operating Environment:

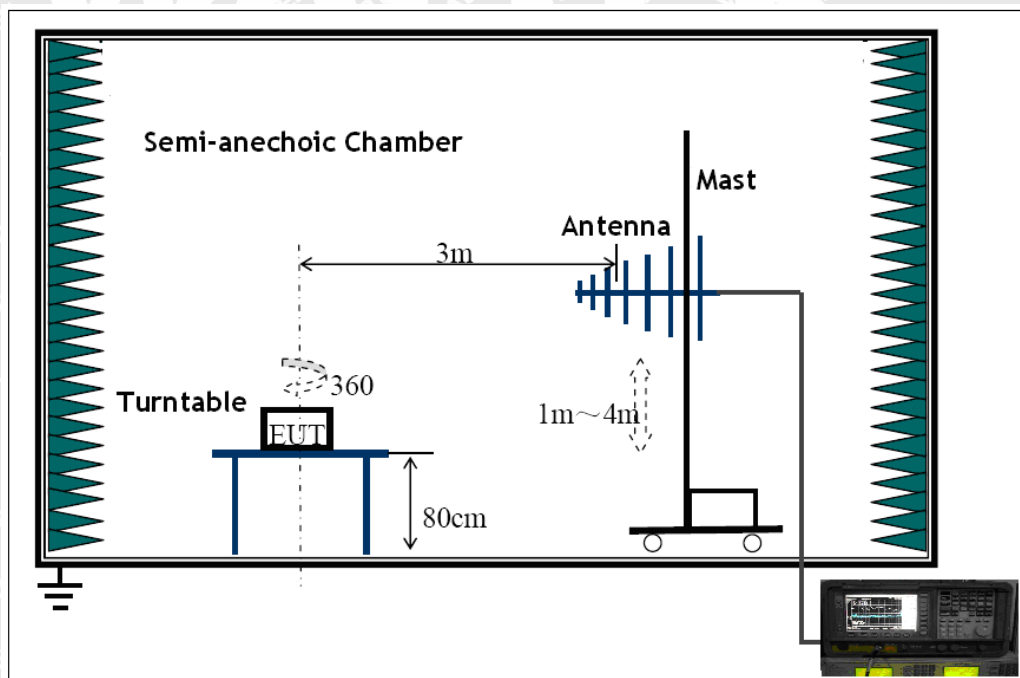
Temperature	: 21.2°C
Humidity	: 54.2%RH
Atmospheric Pressure	: 101.2kPa

EUT Operation:

Input Voltage	: AC 240V/50Hz
Operating Mode	: Working mode

5.2.2 Block Diagram of Test Setup

The Radiated Emission tests were performed in the 3m Semi- Anechoic Chamber test site, using the setup accordance with the CISPR 16-2-3.



5.2.3 Measurement Data

The maximised peak emissions from the EUT was scanned and measured for EUT 0°-360°. Quasi-peak measurements were performed if peak emissions were within 6dB of the limit line.



5.2.4 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Corr. Factor}$$

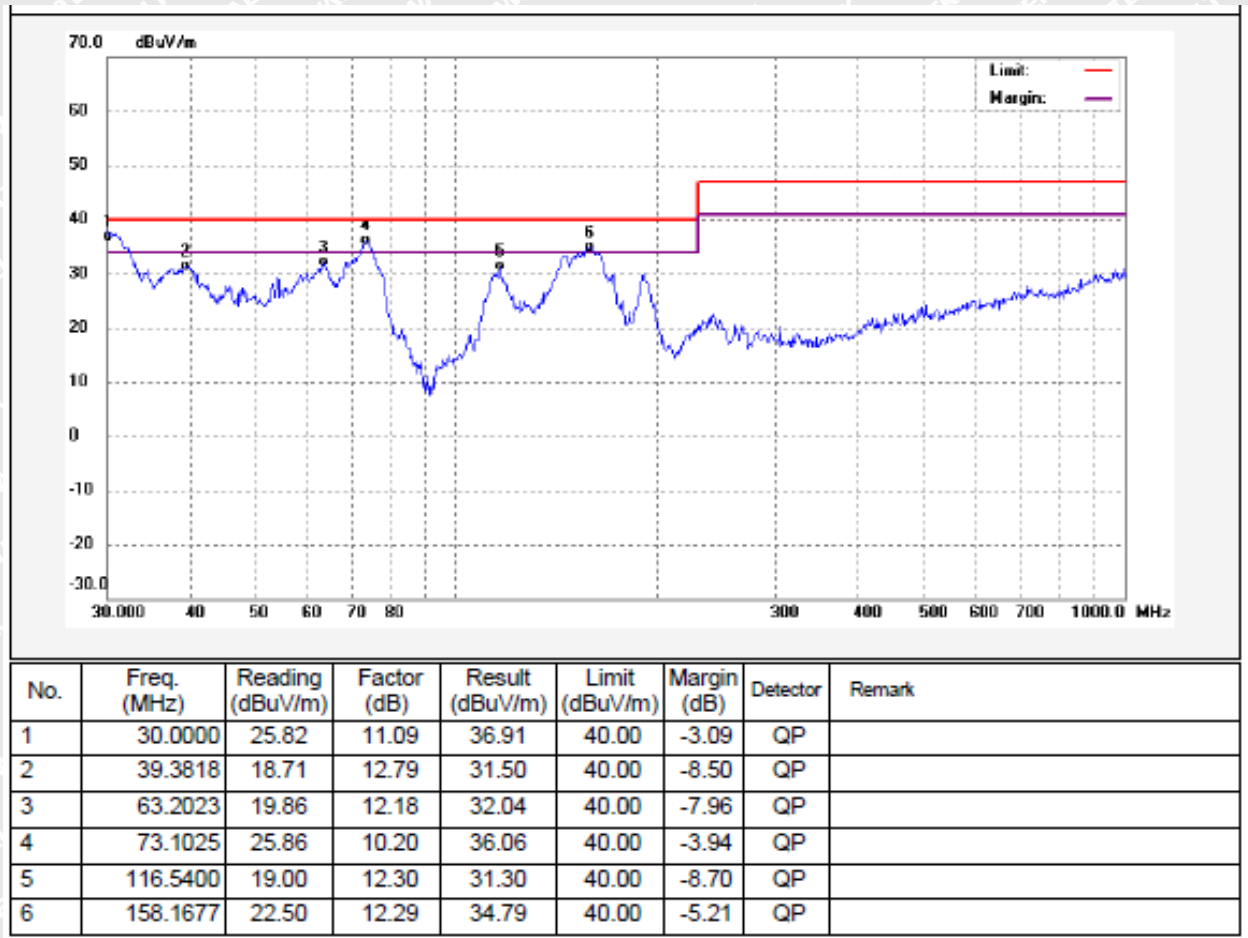
$$\text{Corr. Factor} = \text{Antenna Factor} + \text{Cable Factor} - \text{Amplifier Gain}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the maximum limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Corr. Ampl.} - \text{Limit}$$

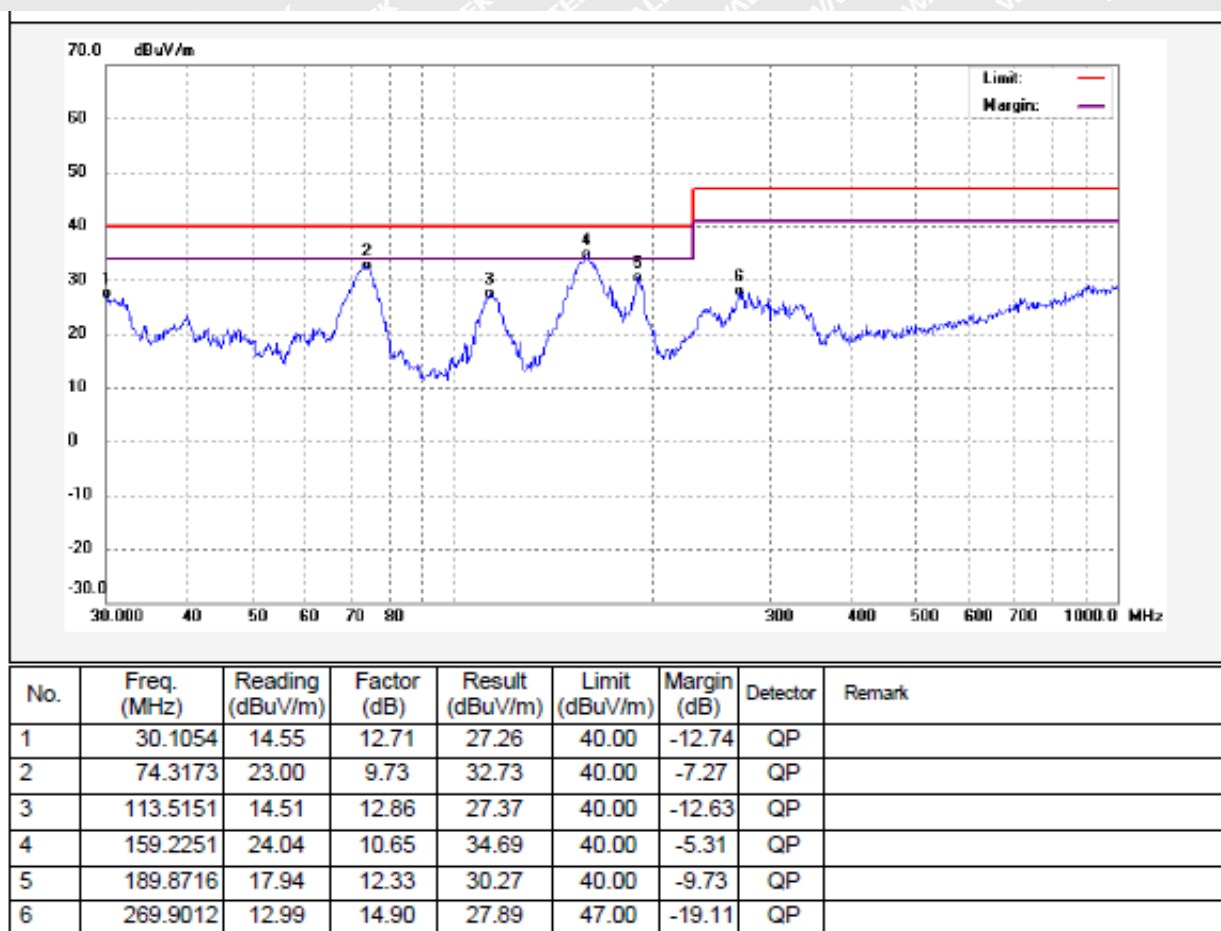
5.2.5 Radiated Emission Test Data

Vertical Polarization





Horizontal Polarization





5.3 Voltage Fluctuation and Flicker

Test Requirement : EN 61000-3-3
Test Method..... : EN 61000-3-3
Test Result : Pass

5.3.1 E.U.T. Operation

Operating Environment:

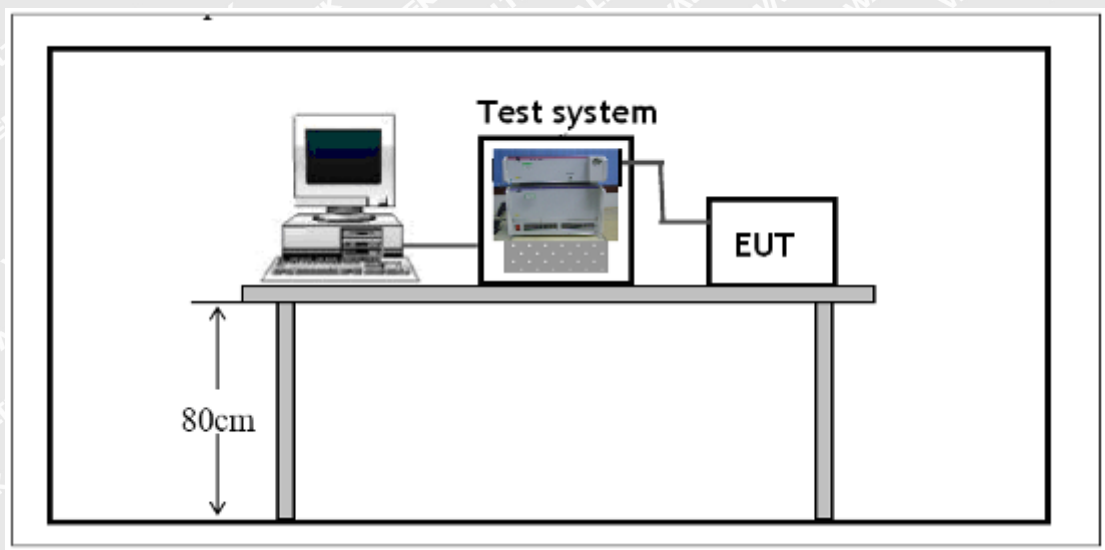
Temperature : 24.8°C
Humidity..... : 49.3%RH
Barometric Pressure..... : 101.2kPa

EUT Operation:

Input Voltage : AC 230V/50Hz
Operating Mode..... : Charging mode

5.3.2 Block Diagram of Setup

The Voltage Fluctuation and Flicker test was performed in accordance with the EN 61000-3-3.



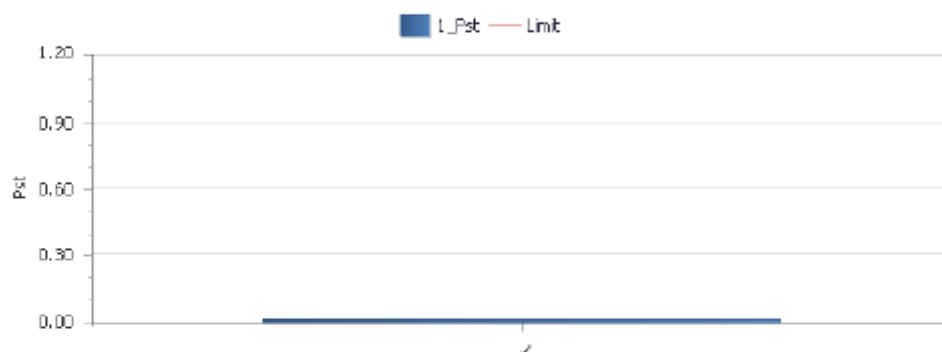


5.3.3 Voltage Fluctuation and Flicker Test Data

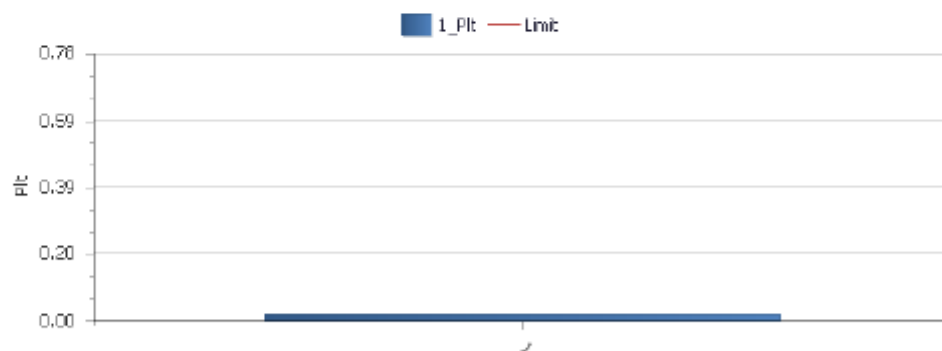
Flicker Test Report IEC 61000-3-3 Ed. 3.1 (2017)

Tester : Luca
Tested : 20W EU plug with Type-C
Device : All Parameters
Test Type : All Parameters
Test Date : 2023-09-22
Start Time : 16:13:12
End Time : 16:23:12
Test Volt. : 230.00V
Comments :
Customer :
Result : PASS

Pst and Limit



Plt and Limit



Relevant Parameter and Judgement During Test Period

Vrms at the end of test(V)	230.04			
Error Max(%)		Test Limit(%)		
T-max(ms)	0.00	Test Limit(ms)	500	Pass
dc(%)	0.00	Test Limit(%)	3.30	Pass
dmax(%)	0.00	Test Limit(%)	4.00	Pass
Pst	0.017	Test Limit	1.000	Pass
Plt	0.017	Test Limit	—	—



6 Immunity Test Results

6.1 Performance Criteria

Performance criterion A: The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.

Performance criterion B: After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test

Performance criterion C: Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

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6.2 Electrostatic Discharge (ESD)

Test Requirement.....	:	EN 55035
Test Method.....	:	IEC 61000-4-2
Test Result.....	:	Pass
Discharge Impedance.....	:	330Ω / 150pF
Discharge Voltage.....	:	Air Discharge: ±8kV Contact Discharge: ±4kV HCP & VCP: ±4kV
Polarity.....	:	Positive & Negative
Number of Discharge.....	:	Minimum 10 times at each test point
Discharge Mode.....	:	Single Discharge
Discharge Period.....	:	1 second minimum

6.2.1 E.U.T. Operation

Operating Environment:

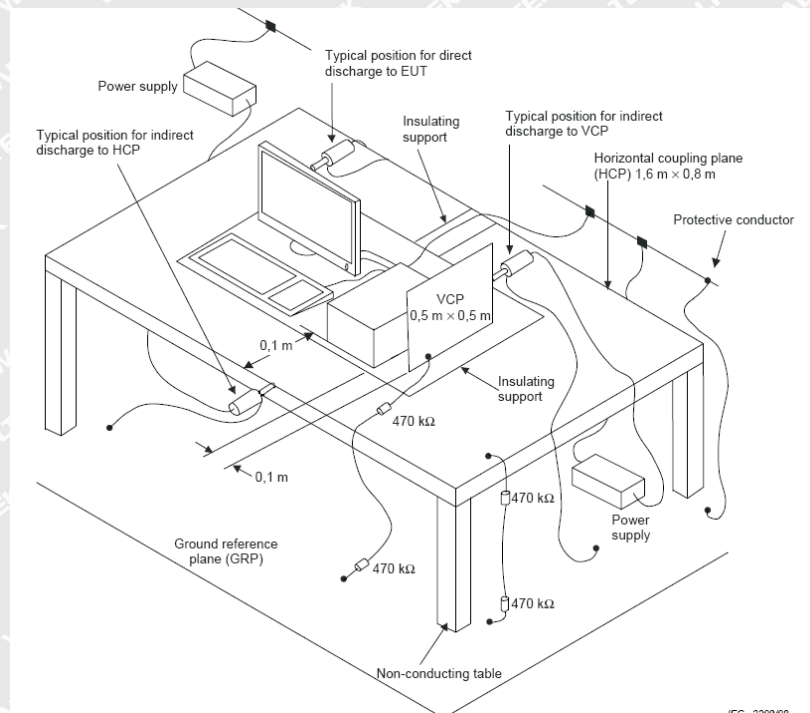
Temperature	:	21.6°C
Humidity	:	51.8%RH
Barometric Pressure	:	101.9kPa

EUT Operation:

Input Voltage	:	AC 230V/50Hz
Operating Mode.....	:	On mode

6.2.2 Block Diagram of Setup

The ESD test was performed in accordance with the IEC 61000-4-2.





6.2.3 Direct Discharge Test Results

Observations:

Test points:

1. All Exposed Surface & Seams;
2. All metallic part

Direct Discharge			Test Results	
Applied Voltage (kV)	Performance Criterion	Test Point	Contact Discharge	Air Discharge
±8	B	1	N/A	Pass*
±4	B	2	Pass*	N/A

Remark:

- * During the test no deviation was detected to the selected operation mode(s)

6.2.4 Indirect Discharge Test Results

Observations:

Test points:

1. All sides.

Indirect Discharge			Test Results	
Applied Voltage (kV)	Performance Criterion	Test Point	Horizontal Coupling	Vertical Coupling
±4	B	1	Pass*	Pass*

Remark:

- * During the test no deviation was detected to the selected operation mode(s)



6.3 Continuous RF Electromagnetic Field Disturbances

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-3
Test Result	: Pass
Frequency Range	: 80MHz to 1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz
Test level	: 3V/m
Modulation	: 80%, 1kHz Amplitude Modulation.
Face of EUT	: Front, Back, Left, Right
Antenna polarisation	: Horizontal & Vertical
Test Distance	: 3m

6.3.1 E.U.T. Operation

Operating Environment:

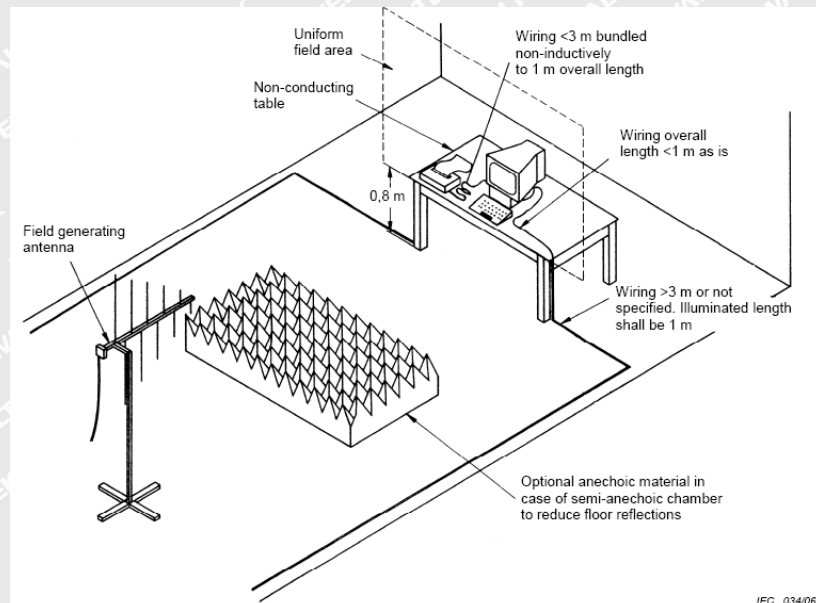
Temperature	: 23.1°C
Humidity	: 52.2%RH
Barometric Pressure	: 101.3kPa

EUT Operation:

Input Voltage	: AC 230V/50Hz
Operating Mode	: On mode

6.3.2 Block Diagram of Setup

The Radio-frequency electromagnetic fields Immunity test was performed in accordance with the IEC 61000-4-3.





6.3.3 Test Results

Frequency	Face of EUT	Antenna polarisation	Test Level	Step Size	Dwell Time	Performance Criterion	Result
80 to 1000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
80 to 1000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
1800MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
1800MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
2600MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
2600MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
3500MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
3500MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
5000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
5000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*

Remark:

- * During the test no deviation was detected to the selected operation mode(s)



6.4 Electrical Fast Transients (EFT)

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-4
Test Result	: Pass
Test Level	: 1.0kV on AC Mains
Polarity	: Positive & Negative
Repetition Frequency	: 5kHz
Burst Duration	: 5/50ns
Test Duration	: 2 minutes per level & polarity

6.4.1 E.U.T. Operation

Operating Environment:

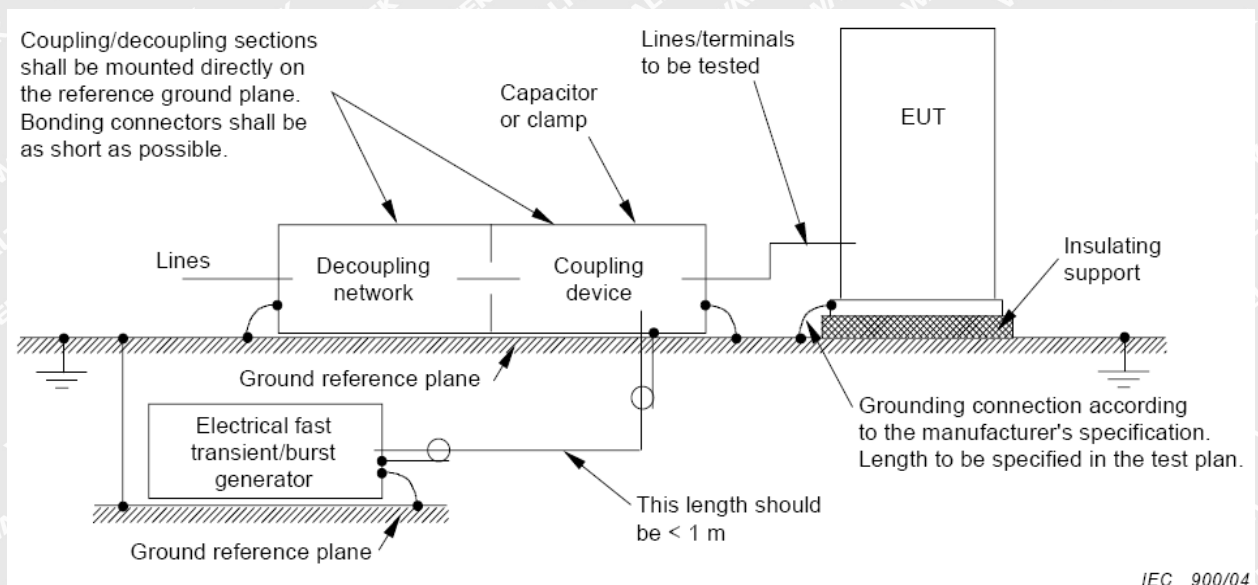
Temperature	: 21.4°C
Humidity	: 51.6%RH
Barometric Pressure	: 101.7kPa

EUT Operation:

Input Voltage	: AC 230V/50Hz
Operating Mode	: On mode

6.4.2 Block Diagram of Setup

The Electrical Fast Transients Immunity test was performed in accordance with the IEC 61000-4-4.





6.4.3 Test Results

Test Port	Test Level(kV)	Performance Criterion	Result
Line-Neutral	± 1.0	B	Pass*

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.5 Surge

Test Requirement	:	EN 55035
Test Method	:	IEC 61000-4-5
Test Result	:	Pass
Test level	:	±1kV Live to Neutral, ±2kV Live to PE and Neutral to PE
Interval	:	60s between each surge
No. of surges	:	five positive and five negative pulses each at 0°, 90°, 180° and at 270°

6.5.1 E.U.T. Operation

Operating Environment:

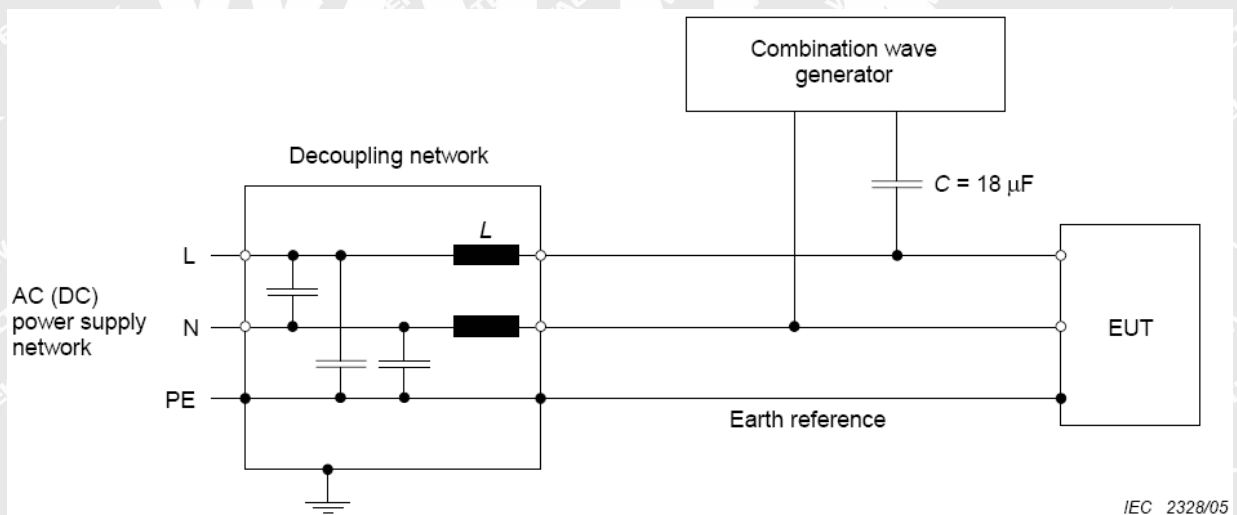
Temperature	:	21.2°C
Humidity	:	51.4%RH
Barometric Pressure	:	101.3kPa

EUT Operation:

Input Voltage	:	AC 230V/50Hz
Operating Mode	:	On mode

6.5.2 Block Diagram of Setup

The Surge Immunity test was performed in accordance with the IEC 61000-4-5.





6.5.3 Test Result

Test Port	Applied Voltage (kV)	Performance criterion	Result
Between Phase And Phase	± 1	B	N/A
Between Live And Neutral	± 1	B	Pass*
Between Live And Earth	± 2	B	N/A
Between Neutral And Earth	± 2	B	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.6 Continuous Induced RF Disturbance

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-6
Test Result	: Pass
Frequency Range	: 0.15 to 10MHz, 10 to 30MHz, 30 to 80MHz
Test level	: 3V r.m.s. / 3~1V r.m.s. / 1V r.m.s. (unmodulated emf into 150 Ω)
Modulation	: 80%, 1kHz Amplitude Modulation.

6.6.1 E.U.T. Operation

Operating Environment:

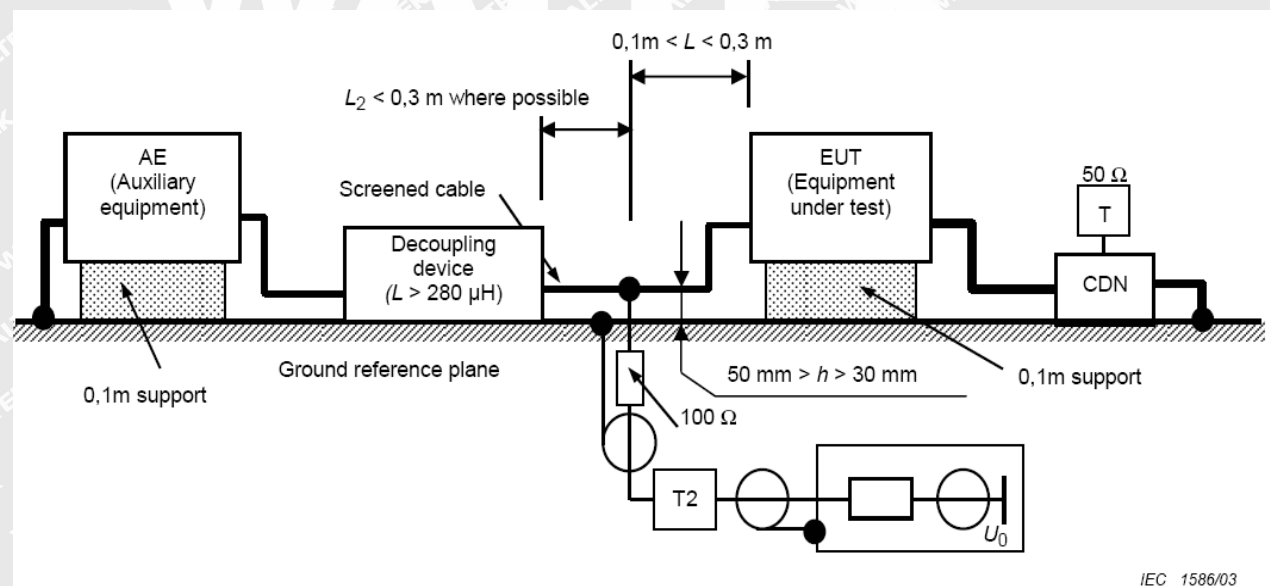
Temperature	: 21.3°C
Humidity	: 51.4%RH
Barometric Pressure	: 101.2kPa

EUT Operation:

Input Voltage	: AC 230V/50Hz
Operating Mode	: On mode

6.6.2 Block Diagram of Setup

The Injected Currents Immunity test was performed in accordance with the IEC 61000-4-6.





6.6.3 Test Results

Frequency	Line	Test Level	Modulation	Step Size	Dwell Time	Performance Criterion	Result
0.15MHz to 10MHz	2 Wire AC Supply Cables	3Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*
10MHz to 30MHz	2 Wire AC Supply Cables	3 to 1 Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*
30MHz to 80MHz	2 Wire AC Supply Cables	1Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.7 Voltage Dips and Interruptions

Test Requirement.....	:	EN 55035
Test Method.....	:	IEC 61000-4-11
Test Result.....	:	Pass
Test Level(Voltage reduction) :	:	>90% & 30 % of Induction
No. of Dips / Interruptions.....	:	1 per Level at 20ms intervals

6.7.1 E.U.T. Operation

Operating Environment:

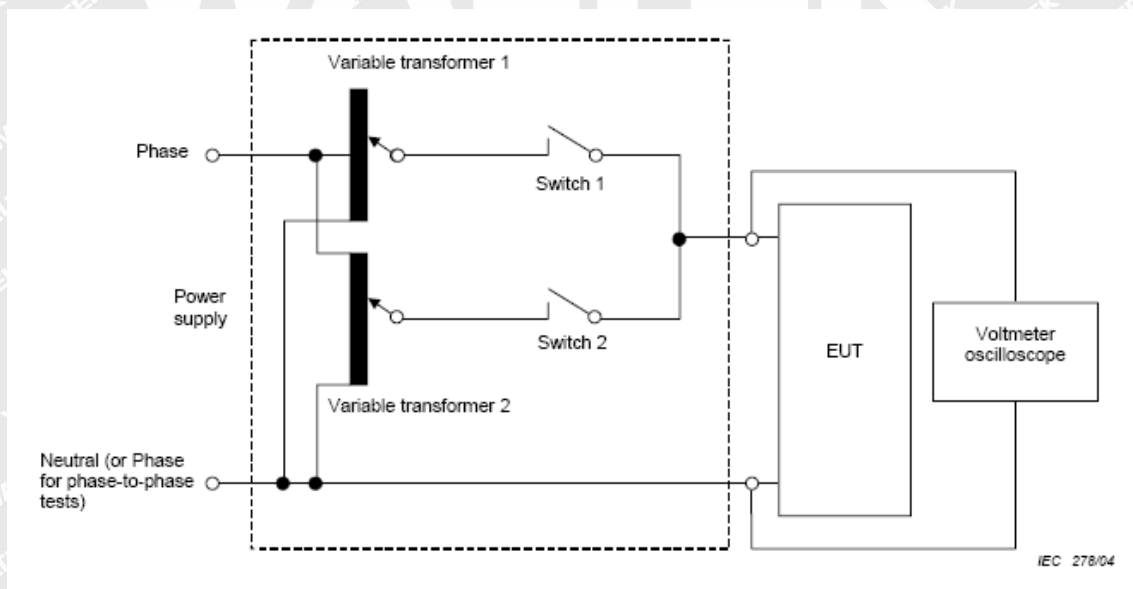
Temperature.....	:	21.5°C
Humidity.....	:	51.2%RH
Barometric Pressure.....	:	101.3kPa

EUT Operation:

Input Voltage.....	:	AC 230V/50Hz
Operating Mode.....	:	On mode

6.7.2 Block Diagram of Setup

The Voltage Dips and Interruptions Immunity test was performed in accordance with the IEC 61000-4-11.





6.7.3 Test Results

Test Item	Test Level in %U _T	Performance criterion	50Hz		60Hz	
			Duration	Result	Duration	Result
Voltage Dips	< 5	B	0.5	Pass*	0.5	N/A
	70	C	25	Pass*	30	N/A
Voltage Interruptions	< 5	C	250	Pass*	300	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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7 Photographs – Test Setup

7.1 Photograph – Mains Terminal Disturbance Voltage Test Setup



7.2 Photograph – Radiated Emission Test Setup

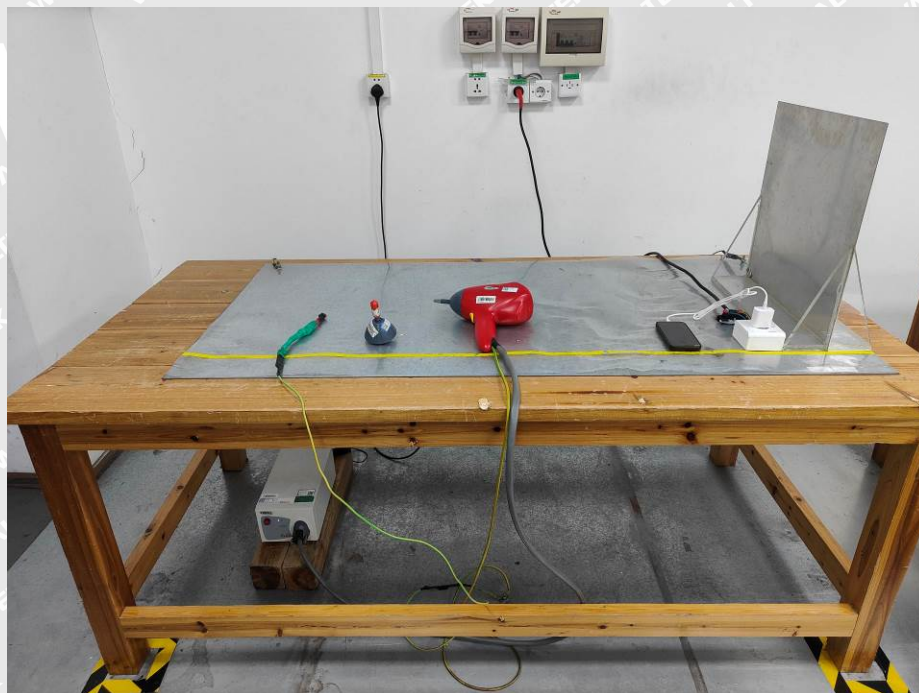




7.3 Photograph – Voltage Fluctuation and Flicker Test Setup



7.4 Photograph – ESD Immunity Test Setup

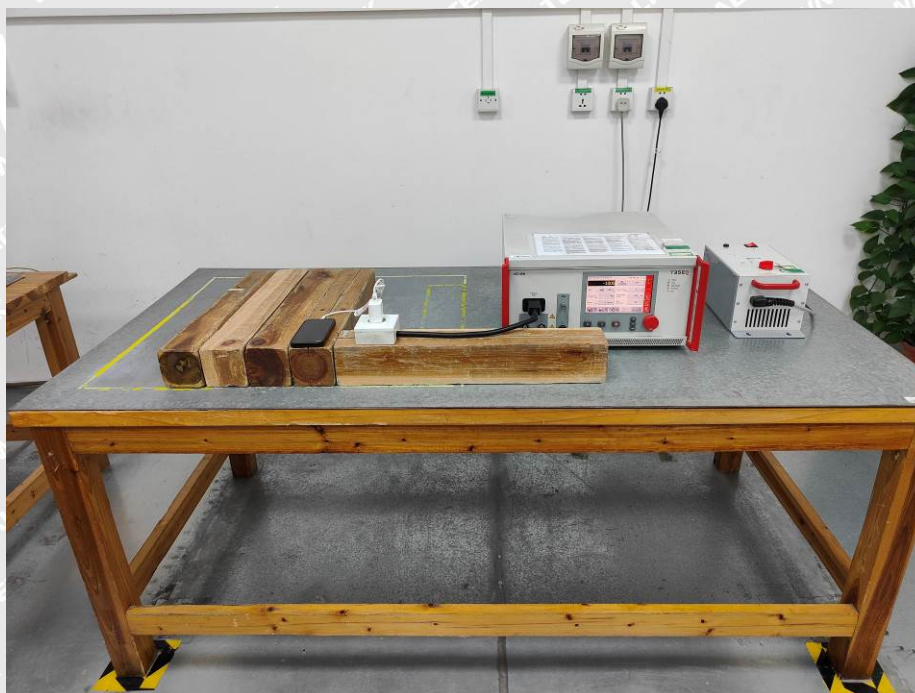




7.5 Photograph – Continuous RF Electromagnetic Field Disturbances Test Setup



7.6 Photograph – EFT Immunity Test Setup

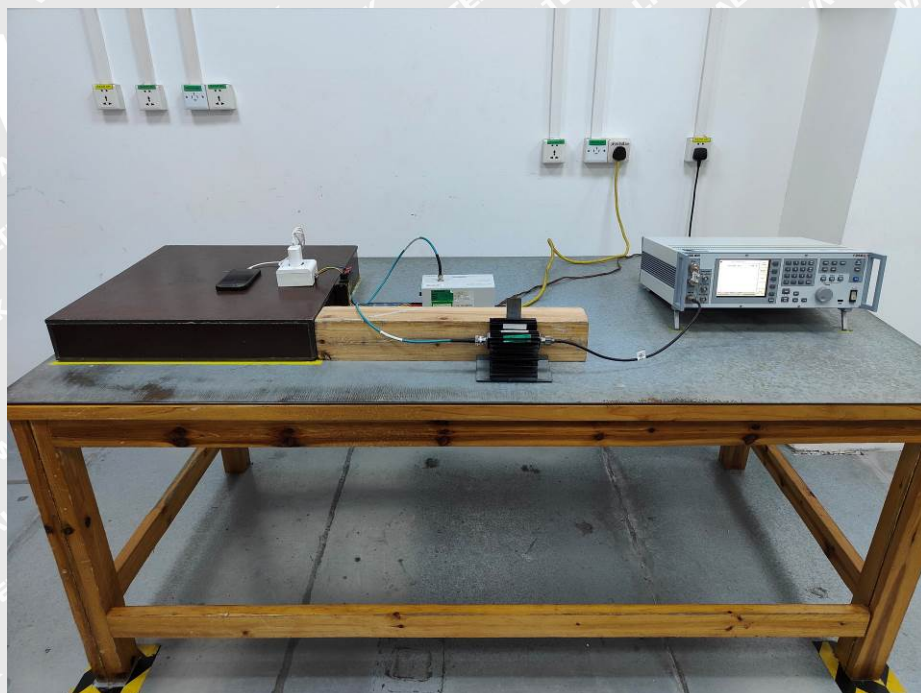




7.7 Photograph – Surge Immunity Test Setup

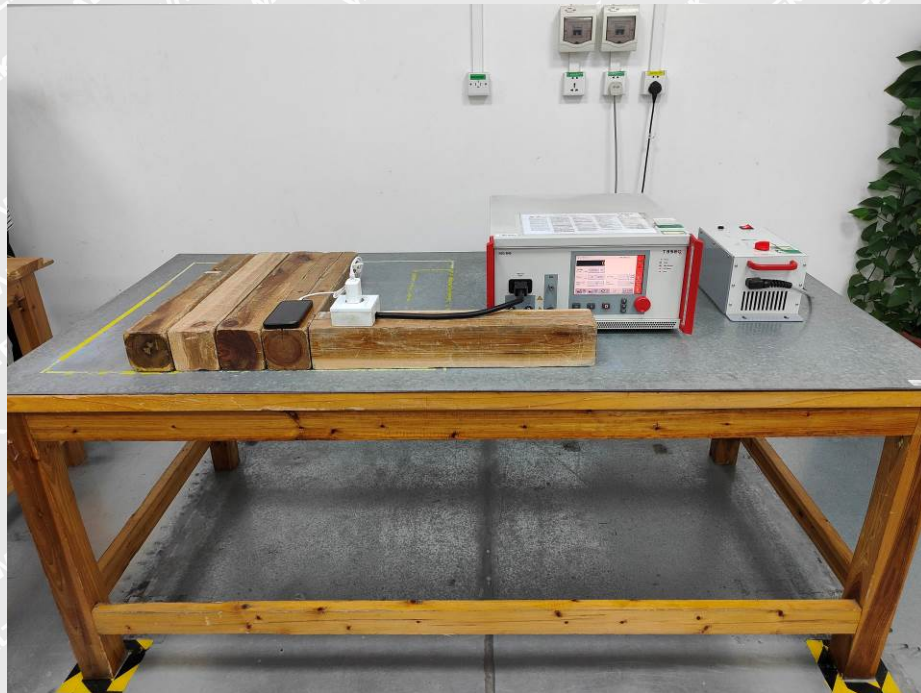


7.8 Photograph – Continuous Induced RF Disturbance Test Setup





7.9 Photograph – Voltage Dips and Interruptions Immunity Test Setup



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8 Photographs – Constructional Details

8.1 EUT – External View



===== End of Report =====